



ALPHA & OMEGA
SEMICONDUCTOR

AON6312

30V N-Channel MOSFET

General Description

- Trench Power MOSFET technology
- Low $R_{DS(ON)}$
- Low Gate Charge
- High Current Capability
- RoHS and Halogen-Free Compliant

Product Summary

V_{DS}	30V
I_D (at $V_{GS}=10V$)	130A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	< 1.85mΩ
$R_{DS(ON)}$ (at $V_{GS}=4.5V$)	< 2.5mΩ

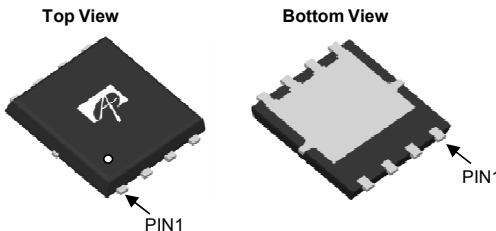
100% UIS Tested
100% R_g Tested



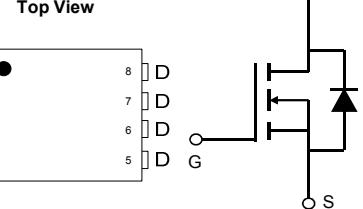
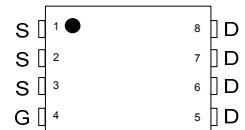
Applications

- DC/DC Converters in Computing
- Isolated DC/DC Converters in Telecom and Industrial
- See Note I

DFN5x6



Top View



Orderable Part Number

AON6312

Package Type

DFN 5x6

Form

Tape & Reel

Minimum Order Quantity

3000

Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current <small>$T_C=25^\circ C$</small>	I_D	130	A
		83	
Pulsed Drain Current ^C	I_{DM}	260	
Continuous Drain Current <small>$T_A=25^\circ C$</small>	I_{DSM}	46	A
		37	
Avalanche Current ^C	I_{AS}	80	A
Avalanche energy <small>$L=0.01mH$</small>	E_{AS}	32	mJ
Drain-Source Spike	V_{SPIKE}	36	V
Power Dissipation ^B	P_D	50	W
		20	
Power Dissipation ^A	P_{DSM}	6.2	W
		4	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	°C

Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient ^A	$R_{\theta JA}$	15	20	°C/W
Maximum Junction-to-Ambient ^{A,D}		40	50	°C/W
Maximum Junction-to-Case	$R_{\theta JC}$	1.9	2.5	°C/W

Electrical Characteristics ($T_J=25^\circ\text{C}$ unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	$\text{ID}=250\mu\text{A}, \text{VGS}=0\text{V}$	30			V
I_{DSS}	Zero Gate Voltage Drain Current	$\text{V}_{\text{DS}}=30\text{V}, \text{V}_{\text{GS}}=0\text{V}$ $T_J=55^\circ\text{C}$		1	5	μA
I_{GSS}	Gate-Body leakage current	$\text{V}_{\text{DS}}=0\text{V}, \text{V}_{\text{GS}}=\pm 20\text{V}$			± 100	nA
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	$\text{V}_{\text{DS}}=\text{V}_{\text{GS}}, \text{I}_{\text{D}}=250\mu\text{A}$	1.3	1.75	2.2	V
$\text{R}_{\text{DS(ON)}}$	Static Drain-Source On-Resistance	$\text{V}_{\text{GS}}=10\text{V}, \text{I}_{\text{D}}=20\text{A}$ $T_J=125^\circ\text{C}$		1.5	1.85	$\text{m}\Omega$
		$\text{V}_{\text{GS}}=4.5\text{V}, \text{I}_{\text{D}}=20\text{A}$		2.0	2.45	$\text{m}\Omega$
g_{FS}	Forward Transconductance	$\text{V}_{\text{DS}}=5\text{V}, \text{I}_{\text{D}}=20\text{A}$		125		S
V_{SD}	Diode Forward Voltage	$\text{I}_{\text{S}}=1\text{A}, \text{V}_{\text{GS}}=0\text{V}$		0.68	1	V
I_{S}	Maximum Body-Diode Continuous Current				60	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	$\text{V}_{\text{GS}}=0\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{f}=1\text{MHz}$		3100		pF
C_{oss}	Output Capacitance			875		pF
C_{rss}	Reverse Transfer Capacitance			105		pF
R_g	Gate resistance	$\text{f}=1\text{MHz}$	1.1	2.3	3.5	Ω
SWITCHING PARAMETERS						
$\text{Q}_g(10\text{V})$	Total Gate Charge	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{I}_{\text{D}}=20\text{A}$		43	65	nC
$\text{Q}_g(4.5\text{V})$	Total Gate Charge			20	30	nC
Q_{gs}	Gate Source Charge			8.5		nC
Q_{gd}	Gate Drain Charge			6		nC
$t_{\text{D(on)}}$	Turn-On DelayTime	$\text{V}_{\text{GS}}=10\text{V}, \text{V}_{\text{DS}}=15\text{V}, \text{R}_L=0.75\Omega, \text{R}_{\text{GEN}}=3\Omega$		11.5		ns
t_r	Turn-On Rise Time			5		ns
$t_{\text{D(off)}}$	Turn-Off DelayTime			40		ns
t_f	Turn-Off Fall Time			8		ns
t_{rr}	Body Diode Reverse Recovery Time	$\text{I}_{\text{F}}=20\text{A}, \text{di/dt}=500\text{A}/\mu\text{s}$		17		ns
Q_{rr}	Body Diode Reverse Recovery Charge	$\text{I}_{\text{F}}=20\text{A}, \text{di/dt}=500\text{A}/\mu\text{s}$		36		nC

A. The value of R_{QJA} is measured with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\text{QJA}} \leq 10\text{s}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.

B. The power dissipation P_D is based on $T_{J(\text{MAX})}=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature $T_{J(\text{MAX})}=150^\circ\text{C}$.

D. The R_{QJA} is the sum of the thermal impedance from junction to case R_{QJC} and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300 μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(\text{MAX})}=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^\circ\text{C}$.

I. For application requiring slow >1ms turn-on/turn-off, please consult AOS FAE for proper product selection.

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TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

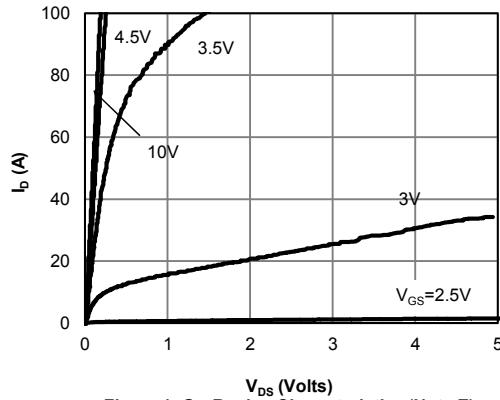


Figure 1: On-Region Characteristics (Note E)

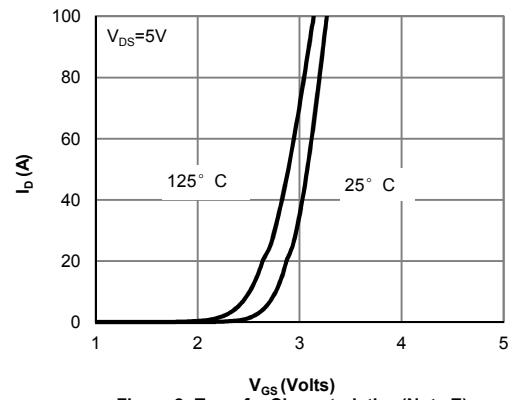


Figure 2: Transfer Characteristics (Note E)

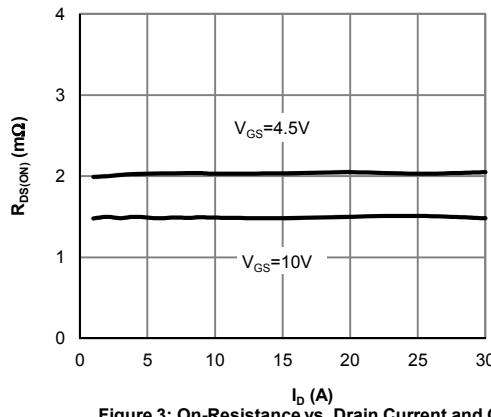


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

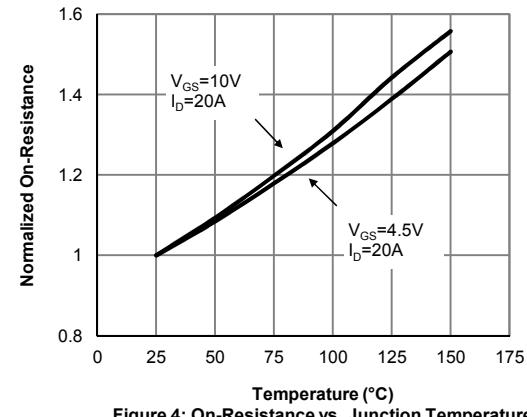


Figure 4: On-Resistance vs. Junction Temperature (Note E)

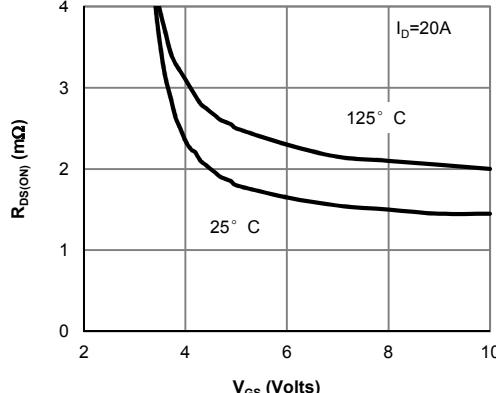


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

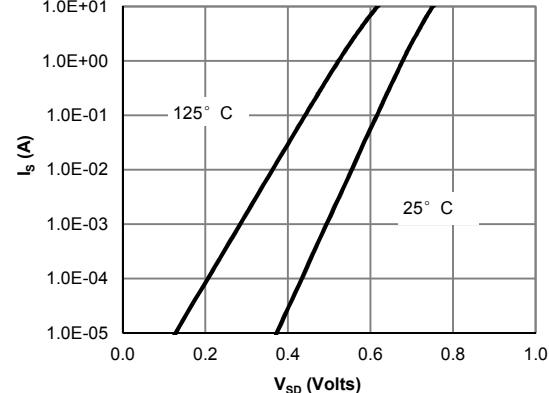


Figure 6: Body-Diode Characteristics (Note E)

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

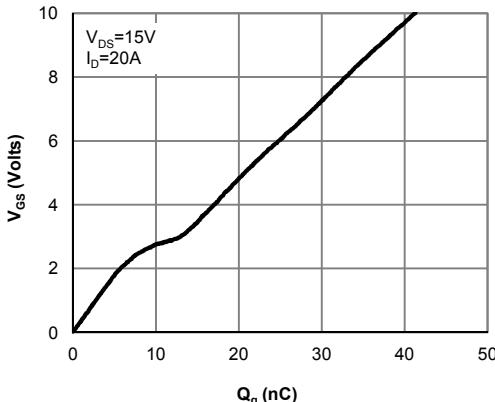


Figure 7: Gate-Charge Characteristics

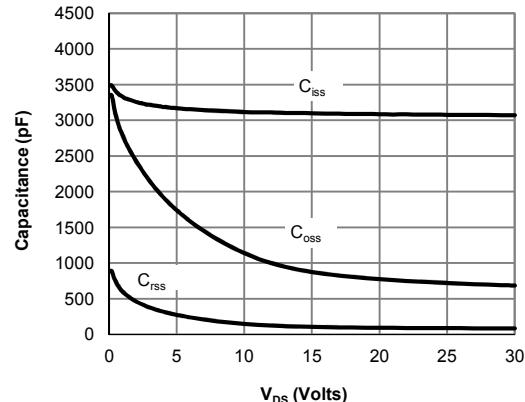


Figure 8: Capacitance Characteristics

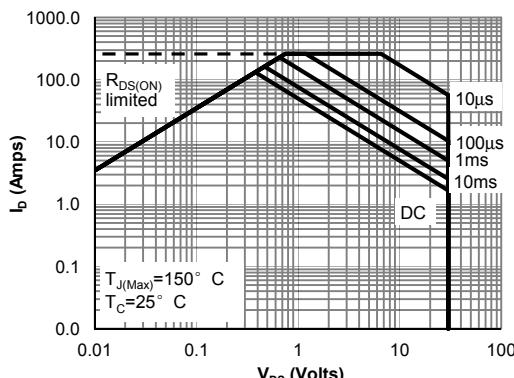


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

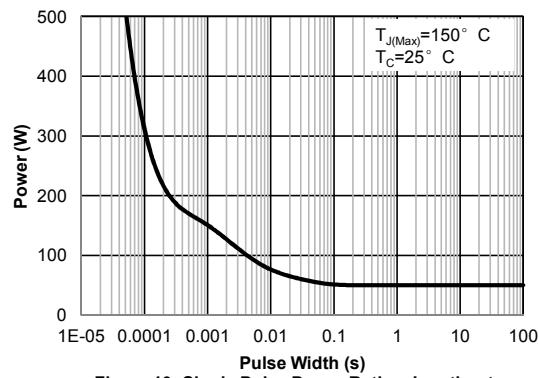


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

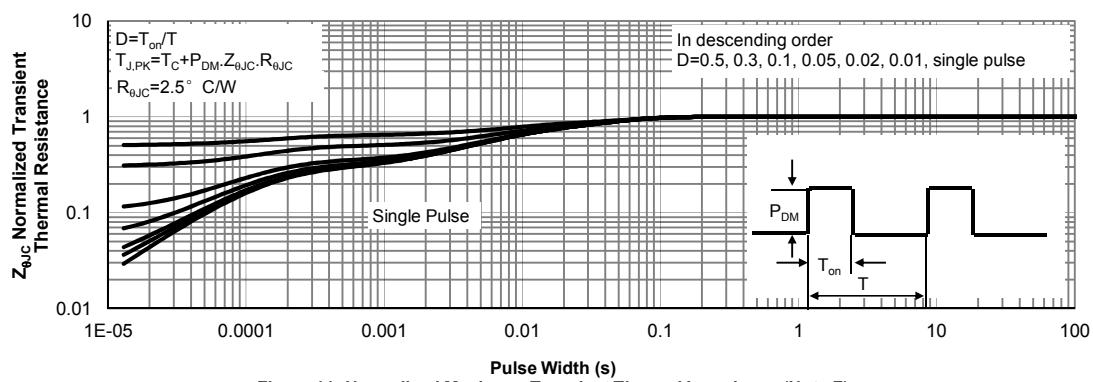


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

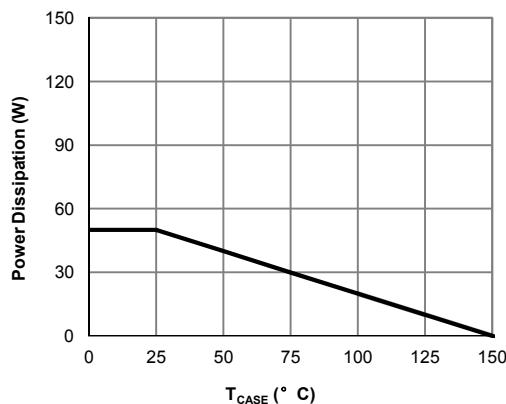

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS


Figure 12: Power De-rating (Note F)

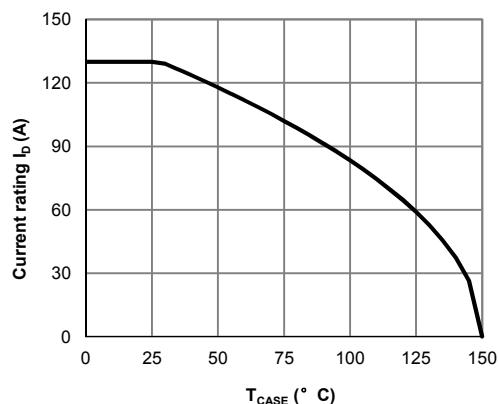


Figure 13: Current De-rating (Note F)

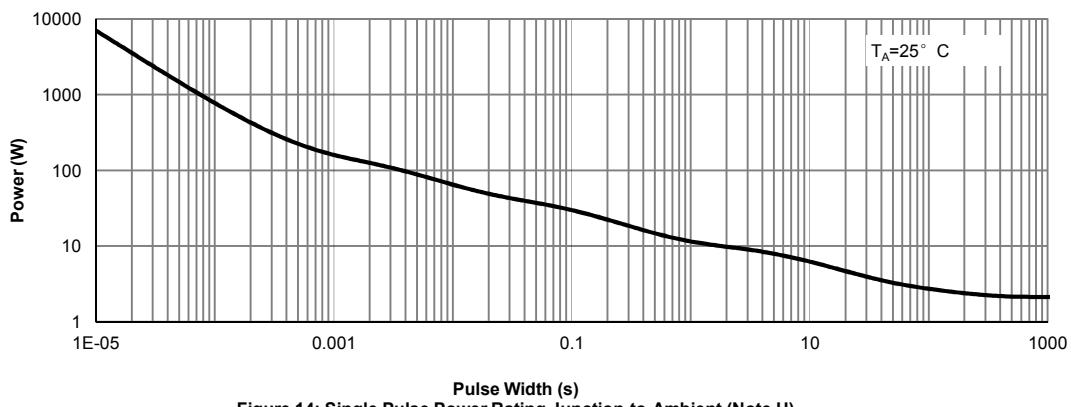


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

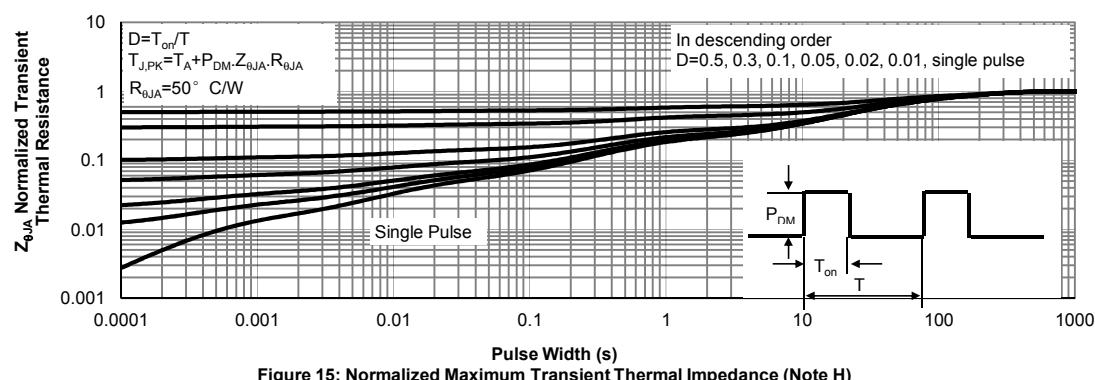


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

Figure A: Gate Charge Test Circuit & Waveforms

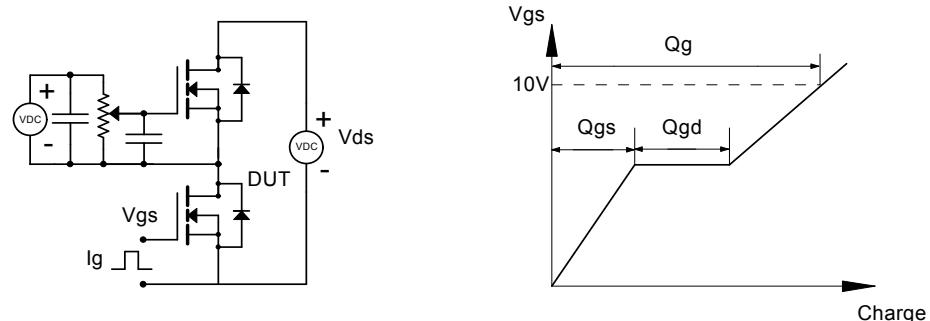


Figure B: Resistive Switching Test Circuit & Waveforms

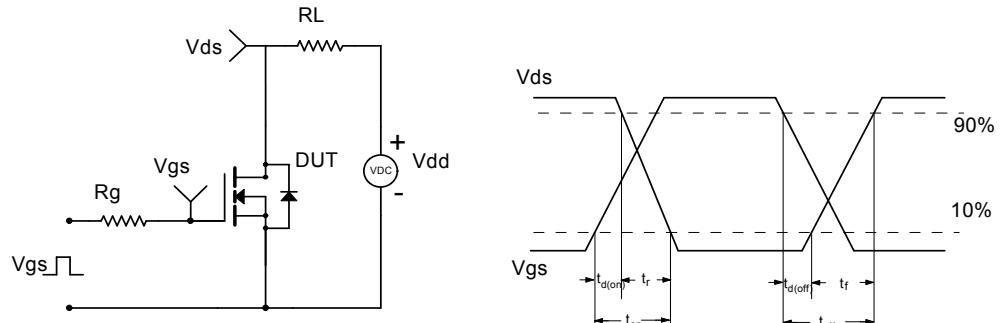


Figure C: Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

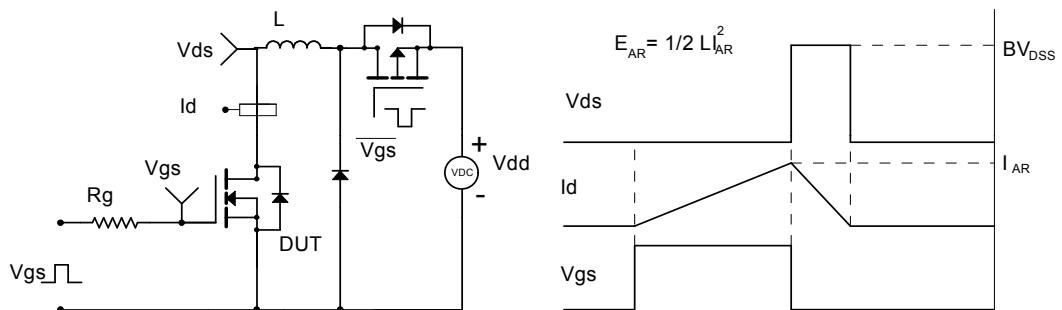


Figure D: Diode Recovery Test Circuit & Waveforms

